**ATS 5034 System-Level Test (SLT) Platform**

Finally...Affordable, High Volume SLT for Integrated Semiconductors

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**An SLT Revolution**

Evolve your SLT test strategy with the new ATS 5034 System-Level Test (SLT) Platform. This revolutionary system delivers a new level of sophisticated testing that automates semiconductor system-level testing on a massive scale, making it easy and affordable to conduct 100% SLT.

With existing low-volume SLT equipment, companies typically test in sample lots, which can lead to expensive escapes. The ATS 5034 SLT Platform transforms this traditionally difficult, expensive test insertion into an easy solution where devices are tested up to x396 in a massively parallel configuration.

Deploy your system to achieve:

- Faster time to volume
- Improved device yields
- The lowest cost of SLT

Today the largest semiconductor companies trust Astronics Test Systems to test billions of devices worldwide.

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**Test it All**

Test all your integrated semiconductors for today’s advanced electronics, including mobile devices, automobile computers, biomedical wearables, and other IoT devices.

This versatile platform performs a variety of test functions: system characterization, system validation, system qualification, system-level test and RMA/failure debug.

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**KEY BENEFITS**

- First massively parallel SLT tester
- Highest UPH for system-level test (up to 5,000 UPH)
- Lowest cost of ownership, lowest cost of test, lowest OPEX
- Easiest-to-operate automation with proven ActivATE™ software
- Best-in-class thermal test
- Built on 20+ years of field-proven SLT technology with billions of devices tested

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Test microprocessors, microcontrollers, and embedded systems

The ATS 5034 SLT Platform configuration.
Test any high-volume integrated semiconductors such as microprocessors, microcontrollers, and embedded systems with this single system. The ATS 5034 SLT Platform handles any package, including:

- SoCs
- SiPs
- Other modules or combinations of modules

Test identical devices or configure your system for mixed-use. High throughput volume of up to 5,000 UPH is standard, or specify a low-to-mid-volume configuration to suit your needs.

**Significantly Reduce Your Costs.**
The ATS 5034 SLT Platform makes SLT affordable, which means you can shift to a 100% SLT strategy to improve yields and weed out costly defects. Count on the platform to:

- Slash your test costs by testing hundreds of devices in parallel
- Save factory floor footprint costs by replacing multiple testers with this single platform
- Cut operating expenses with fewer operators

**Time-Proven Test Executive Software.** The platform integrates our ActivATE™ software, a powerful multi-threading framework that manages a test sequencer, a device manager, and an IDE (Integrated Development Environment). The IDE enables the test engineer to edit and build a test program using popular production languages including C#, VB.NET, or VBScript. Design a test sequence for a single site, and the ATS 5034 SLT Platform easily scales that sequence to hundreds of sites.

**Global Installation and Support.**
We employ teams worldwide to install your system, train your personnel, and provide maintenance at your designated factory.

**Get Started Today.**
For additional details or to schedule a demonstration, please contact Astronics Test Systems.

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AstronicsTestSystems.com

<table>
<thead>
<tr>
<th>SPECIFICATION</th>
<th>DESCRIPTION</th>
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<tbody>
<tr>
<td><strong>CAPACITY</strong></td>
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<tr>
<td>Devices</td>
<td>Up to 396, simultaneously</td>
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<tr>
<td>Throughput</td>
<td>Up to 5,000 UPH</td>
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<tr>
<td>Test Times</td>
<td>Customizable</td>
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<tr>
<td><strong>GENERAL</strong></td>
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<tr>
<td>Custom options</td>
<td>Thermal stress test, custom test development, test program migration, others</td>
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<tr>
<td>Device types</td>
<td>Microprocessors, microcontrollers, embedded systems, etc.</td>
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<tr>
<td>Device packages</td>
<td>SoC, SiP, modules, etc.</td>
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<tr>
<td><strong>THERMAL</strong></td>
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<tr>
<td>Temp range and control</td>
<td>Range of 0° C to &gt; 150° C with ±1° C DUT temperature control, typical</td>
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<tr>
<td>Mechanical</td>
<td>Two-phase refrigeration-based cooling plus heating circuitry</td>
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<tr>
<td><strong>ACTIVATE™ SOFTWARE</strong></td>
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<td>Results logging</td>
<td>Logs pass/fail results and drives product pass/fail binning</td>
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<td>Test deployment</td>
<td>Enables up to 36 test interface units (TIUs) to execute test programs in parallel</td>
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<tr>
<td>Input/Output</td>
<td>Support for multiple schemes; interfaces with factory ERP and production management software</td>
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